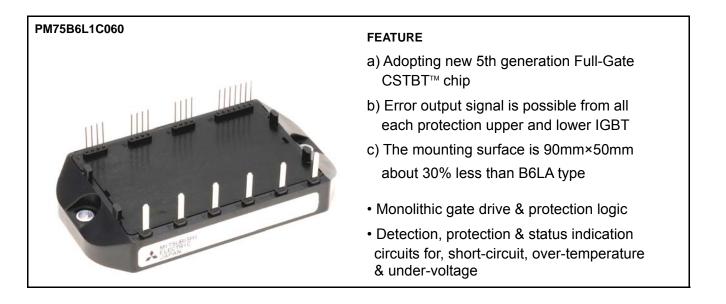
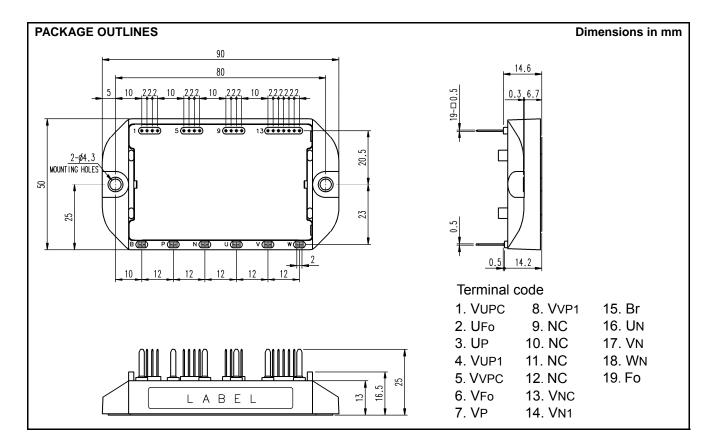
### FLAT-BASE TYPE INSULATED PACKAGE



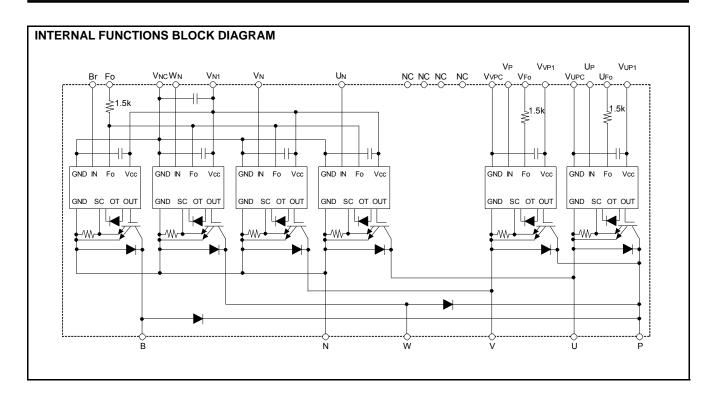
### APPLICATION

Photo voltaic power conditioner





#### FLAT-BASE TYPE INSULATED PACKAGE



### MAXIMUM RATINGS (T<sub>j</sub> = 25°C, unless otherwise noted)

### **INVERTER PART**

Symbol	Parameter	Conditions	Ratings	Unit
V <sub>CES</sub>	Collector-Emitter Voltage	$V_D$ =15V, $V_{CIN}$ =15V	600	V
Ic	Collector Current	T <sub>c</sub> =25°C	75	Α
I <sub>CRM</sub>	Collector Current	Pulse	150	
P <sub>tot</sub>	Total Power Dissipation	T <sub>c</sub> =25°C	201	W
I <sub>E</sub>	Emitter Current	T <sub>c</sub> =25°C	75	Δ
I <sub>ERM</sub>	(Free wheeling Diode Forward current)	Pulse	150	A
Tj	Junction Temperature		-20 ~ +150	°C

\*: Tc measurement point is just under the chip.

#### CONVERTER PART

Symbol	Parameter	Conditions	Ratings	Unit
V <sub>CES</sub>	Collector-Emitter Voltage	V <sub>D</sub> =15V, V <sub>CIN</sub> =15V	600	V
I <sub>C</sub>	Collector Current	T <sub>c</sub> =25°C	75	Α
I <sub>CRM</sub>		Pulse	150	A
P <sub>tot</sub>	Total Power Dissipation	T <sub>c</sub> =25°C	201	W
Ι <sub>Ε</sub>	Emitter Current	T <sub>c</sub> =25°C	75	Α
I <sub>ERM</sub>	(Free wheeling Diode Forward current)	Pulse	150	
I <sub>F</sub>	Di Forward Current	T <sub>c</sub> =25°C	75	Α
V <sub>R(DC)</sub>	Di Rated DC Reverse Voltage	T <sub>c</sub> =25°C	600	V
Tj	Junction Temperature		-20 ~ +150	°C

\*: Tc measurement point is just under the chip.



FLAT-BASE TYPE INSULATED PACKAGE

#### CONTROL PART

Symbol	Parameter	Conditions	Ratings	Unit
VD	Supply Voltage	Applied between : $V_{UP1}$ - $V_{UPC}$ , $V_{VP1}$ - $V_{VPC}$ , $V_{N1}$ - $V_{NC}$	20	V
V <sub>CIN</sub>	Input Voltage	$\begin{array}{c} \text{Applied between : } \text{UP-V}_{\text{UPC}}, \text{VP-V}_{\text{VPC}}, \\ \text{UN} \cdot \text{VN} \cdot \text{WN} \cdot \text{Br-V}_{\text{NC}} \end{array}$	20	V
V <sub>FO</sub>	Fault Output Supply Voltage	Applied between : UFo-V <sub>UPC</sub> , VFo-V <sub>VPC</sub> , Fo-V <sub>NC</sub>	20	V
I <sub>FO</sub>	Fault Output Current	Sink current at UFo, VFo, Fo terminals	20	mA

### TOTAL SYSTEM

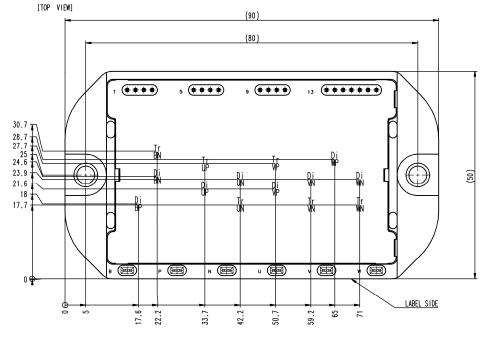
Symbol	Parameter	Conditions	Ratings	Unit
V <sub>CC(PROT)</sub>	Supply Voltage Protected by SC	$V_D = 13.5V \sim 16.5V$ Inverter Part, T <sub>i</sub> =+125°C Start	450	V
V <sub>CC(surge)</sub>	Supply Voltage (Surge)	Applied between : P-N, Surge value	500	V
T <sub>stg</sub>	Storage Temperature		-40 ~ +125	°C
V <sub>isol</sub>	Isolation Voltage	60Hz, Sinusoidal, Charged part to Base plate, AC 1min, RMS	2500	V

\*:  $T_{\text{C}}$  measurement point is just under the chip.

#### THERMAL RESISTANCE

Symbol	Parameter	Conditions		Limits			Unit
Symbol	i arameter	Conditions		Min.	Тур.	Max.	Onic
R <sub>th(j-c)Q</sub>	Thermal Resistance	Inverter, IGBT (per 1 element) (Note	e.1)	-	-	0.62	
R <sub>th(j-c)D</sub>		Inverter, FWDi (per 1 element) (Note	e.1)	-	-	1.06	
R <sub>th(j-c)Q</sub>		Converter, IGBT (per 1 element) (Note	e.1)	-	-	0.62	
R <sub>th(j-c)D</sub>		Converter, FWDi (per 1 element) (Note	e.1)	-	-	1.06	K/W
R <sub>th(j-c)D</sub>		Converter, Di (per 1 element) (Note	e.1)	-	-	1.06	
R <sub>th(c-s)</sub>	Contact Thermal Resistance	Case to heat sink, (per 1 module) Thermal grease applied (Note	e.1)	-	0.06	-	

Note.1: If you use this value,  $R_{th(s-a)}$  should be measured just under the chips.





FLAT-BASE TYPE INSULATED PACKAGE

### **ELECTRICAL CHARACTERISTICS** (Tj = 25°C, unless otherwise noted) **INVERTER PART**

Symbol	Parameter	Condition	Conditions		Limits			Unit
Symbol	Faiallietei	Condition	15		Min.	Тур.	Max.	Onit
V <sub>CEsat</sub>	Collector-Emitter Saturation	V <sub>D</sub> =15V, I <sub>C</sub> =75A		T <sub>j</sub> =25°C	-	2.2	2.7	V
V CEsat	Voltage	V <sub>CIN</sub> =0V, Pulsed (Fi	g. 1)	T <sub>j</sub> =125°C	-	2.2	2.7	v
V <sub>EC</sub>	Emitter-Collector Voltage	I <sub>E</sub> =75A, V <sub>D</sub> =15V, V <sub>CIN</sub> = 15V		(Fig. 2)	-	2.4	3.3	V
t <sub>on</sub>					0.1	0.5	1.2	
t <sub>rr</sub>		$V_D=15V, V_{CIN}=0V \leftrightarrow 15V$			-	0.1	0.2	
t <sub>c(on)</sub>	Switching Time	V <sub>CC</sub> =300V, I <sub>C</sub> =75A T <sub>i</sub> =125°C			-	0.15	0.3	μS
t <sub>off</sub>		Inductive Load (Fig. 3,4)	(Fig. 3.4)	-	1.1	2.0		
t <sub>c(off)</sub>				(	-	0.2	0.4	
	I <sub>CES</sub> Collector-Emitter Cut-off Current V <sub>CE</sub> =V <sub>CES</sub> , V <sub>D</sub> =15V , V <sub>CIN</sub> =15V (I		Tj=25°C	-	-	1	mA	
CES		$v_{CE} - v_{CES}$ , $v_D - 15V$ , $v_{CIN} - 15V$ (I	i iy. 5)	T <sub>j</sub> =125°C	-	-	10	ШA

### CONVERTER PART

Symbol	Parameter	Conditions		Limits			Unit	
Symbol	Falametei	Conu	Conditions		Min.	Тур.	Max.	Onit
V <sub>CEsat</sub>	Collector-Emitter Saturation	V <sub>D</sub> =15V, I <sub>C</sub> =75A		T <sub>j</sub> =25°C	-	2.2	2.7	V
V CEsat	Voltage	V <sub>CIN</sub> =0V, Pulsed	V <sub>CIN</sub> =0V, Pulsed (Fig. 1)	T <sub>j</sub> =125°C	-	2.2	2.7	v
V <sub>EC</sub>	Emitter-Collector Voltage	$I_E$ =75A, $V_D$ =15V, $V_{CIN}$ = 15V		(Fig. 2)	-	2.4	3.3	V
V <sub>FM</sub>	Di Forward Voltage	I <sub>F</sub> =75A			-	2.4	3.3	V
t <sub>on</sub>					0.1	0.5	1.2	
t <sub>rr</sub>		$V_D=15V, V_{CIN}=0V \leftrightarrow 15V$			-	0.1	0.2	
t <sub>c(on)</sub>	Switching Time	V <sub>CC</sub> =300V, I <sub>C</sub> =75A T <sub>i</sub> =125°C			-	0.15	0.3	μS
t <sub>off</sub>		Inductive Load		(Fig. 3,4)	-	1.1	2.0	
t <sub>c(off)</sub>				(	-	0.2	0.4	
	Collector-Emitter Cut-off			T <sub>j</sub> =25°C	-	-	1	m۸
I <sub>CES</sub> Current	Current	$V_{CE}=V_{CES}, V_{D}=15V, V_{CIN}=15V$	v (FIY. 5)	T <sub>j</sub> =125°C	-	-	10	mA

### CONTROL PART

Symbol	ymbol Parameter Conditions		Conditions				Unit
Symbol				Min.	Тур.	Max.	Onit
1	Circuit Current	V <sub>D</sub> =15V, V <sub>CIN</sub> =15V	V <sub>N1</sub> -V <sub>NC</sub>	-	6.5	12	mA
I <sub>D</sub>		VD-13V, VCIN-13V	V*P1-V*PC	-	1.6	4.0	ШA
V <sub>th(ON)</sub>	Input ON Threshold Voltage	Applied between : UP-V <sub>UPC</sub> , VP-V <sub>VPC</sub> ,		1.2	1.5	1.8	v
$V_{\text{th(OFF)}}$	Input OFF Threshold Voltage	$UN \cdot VN \cdot WN \cdot Br - V_{NC}$		1.7	2.0	2.3	V
SC	Short Circuit Trip Level	-20≤Tj≤125°C, V <sub>D</sub> =15V	(Fig. 3, 6)	112	-	-	Α
$t_{\text{off}(\text{SC})}$	Short Circuit Current Delay Time	V <sub>D</sub> =15V	(Fig. 3, 6)	-	0.2	-	μS
OT	Over Temperature Drotestion		Trip level	135	-	-	°C
OT <sub>(hys)</sub>	Over Temperature Protection	Detect Temperature of IGBT chip	Hysteresis	-	20	-	C
UVt	Supply Circuit Under-Voltage	-20≤Tj≤125°C	Trip level	11.5	12.0	12.5	v
UVr	Protection	-2051j5125 C	Reset level	-	12.5	-	v
I <sub>FO(H)</sub>	Fault Output Ourrant		(Nata 2)	-	-	0.01	
I <sub>FO(L)</sub>	<ul> <li>Fault Output Current</li> </ul>	V <sub>D</sub> =15V, V <sub>FO</sub> =15V	(Note.2)	-	10	15	mA
t <sub>FO</sub>	Fault Output Pulse Width	V <sub>D</sub> =15V	(Note.2)	1.0	1.8	-	ms

Note.2: Fault output is given only when the internal SC, OT & UV protections schemes of either upper or lower arm device operate to protect it.



FLAT-BASE TYPE INSULATED PACKAGE

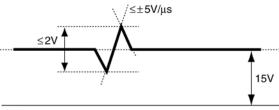
### MECHANICAL RATINGS AND CHARACTERISTICS

Symbol Parameter	Deremeter	Conditions		Limits		
	Conduions		Тур.	Max.	Unit	
Ms	Mounting Torque	Mounting part screw : M4	1.4	1.65	1.9	N∙m
m	Weight	-	-	135	-	g

### **RECOMMENDED CONDITIONS FOR USE**

Symbol	Parameter	Conditions	Recommended value	Unit
V <sub>cc</sub>	Supply Voltage	Applied across P-N terminals	≤ 450	V
V <sub>D</sub>	Control Supply Voltage	$ \begin{array}{c} \mbox{Applied between : } V_{UP1} - V_{UPC}, \\ V_{VP1} - V_{VPC}, V_{N1} - V_{NC} \end{array} (Note. $	3) 15.0±1.5	V
V <sub>CIN(ON)</sub>	Input ON Voltage	Applied between : UP-V <sub>UPC</sub> , VP-V <sub>VPC</sub> ,	≤ 0.8	V
$V_{\text{CIN(OFF)}}$	Input OFF Voltage	UN·VN·WN·Br -V <sub>NC</sub>	≥ 9.0	v
f <sub>PWM</sub>	PWM Input Frequency	Using Application Circuit of Fig. 8	≤ 20	kHz
t <sub>dead</sub>	Arm Shoot-through Blocking Time	For IPM's each input signals (Fig.	7) ≥ 2.0	μS
lo	Module Operating Current	RMS	≤ 30	А

Note.3: With ripple satisfying the following conditions: dv/dt swing ≤ ±5V/µs, Variation ≤ 2V peak to peak



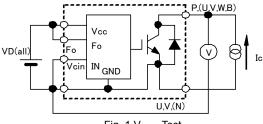
GND



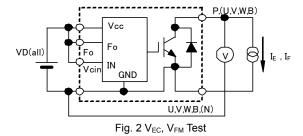
#### PRECAUTIONS FOR TESTING

- 1. Before applying any control supply voltage (V<sub>D</sub>), the input terminals should be pulled up by resistors, etc. to their corresponding supply voltage and each input signal should be kept off state.
- After this, the specified ON and OFF level setting for each input signal should be done.
- 2. When performing "SC" tests, the turn-off surge voltage spike at the corresponding protection operation should not be allowed to rise above  $V_{CES}$  rating of the device.

(These test should not be done by using a curve tracer or its equivalent.)







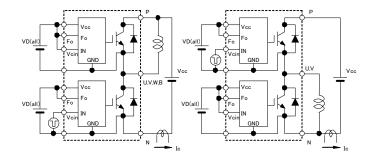
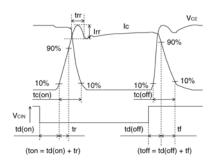
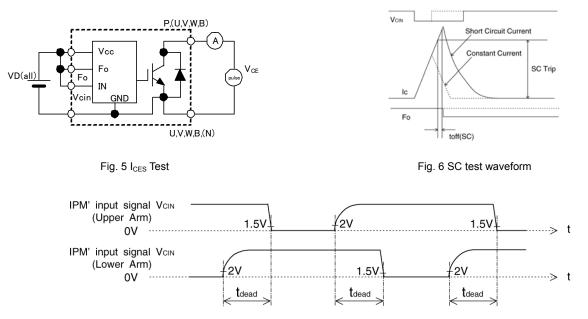


Fig. 3 Switching time and SC test circuit



#### Fig. 4 Switching time test waveform



1.5V: Input on threshold voltage Vth(on) typical value, 2V: Input off threshold voltage Vth(off) typical value



FLAT-BASE TYPE INSULATED PACKAGE

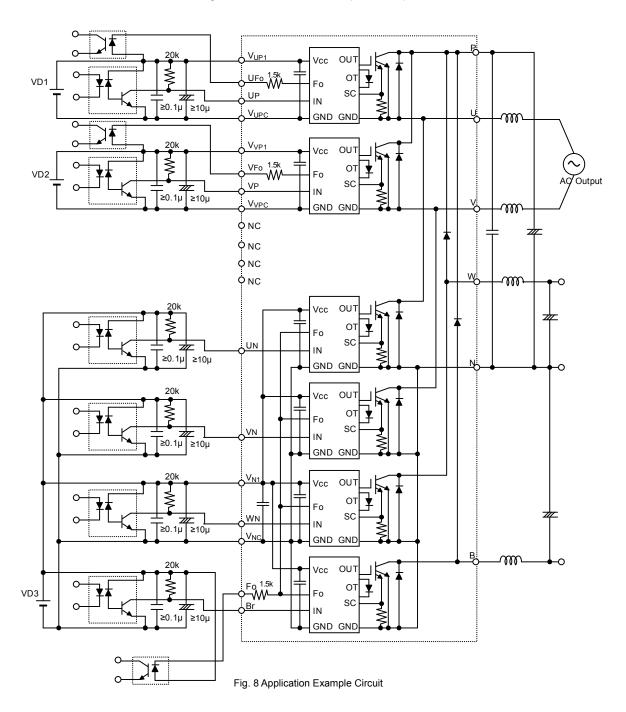


Fig. 7 Dead time measurement point example

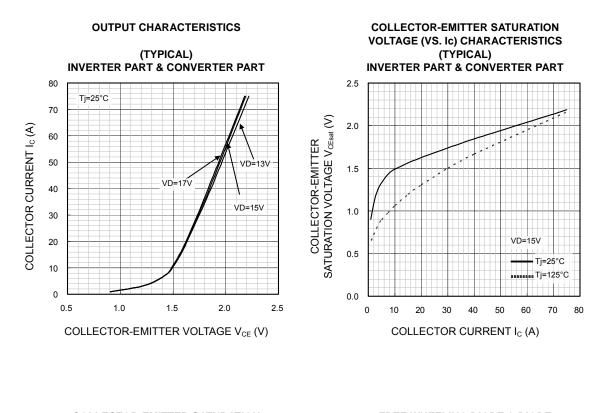
### NOTES FOR STABLE AND SAFE OPERATION ;

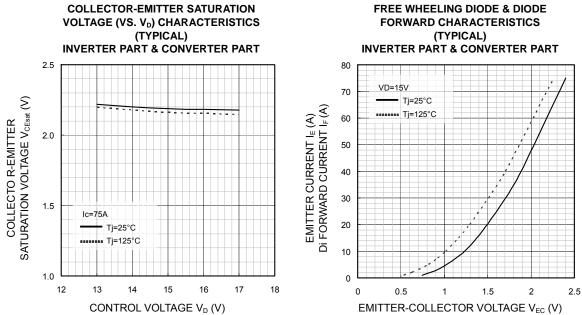
- Design the PCB pattern to minimize wiring length between opto-coupler and IPM's input terminal, and also to minimize the stray capacity between the input and output wirings of opto-coupler.
- Connect low impedance capacitor between the Vcc and GND terminal of each fast switching opto-coupler.
- Fast switching opto-couplers: t<sub>PLH</sub>, t<sub>PHL</sub> ≤ 0.8µs, Use High CMR type.
- Slow switching opto-coupler: CTR > 100%
- Use 3 isolated control power supplies (V<sub>D</sub>). Also, care should be taken to minimize the instantaneous voltage charge of the power supply.
- Make inductance of DC bus line as small as possible, and minimize surge voltage using snubber capacitor between P and N terminal.



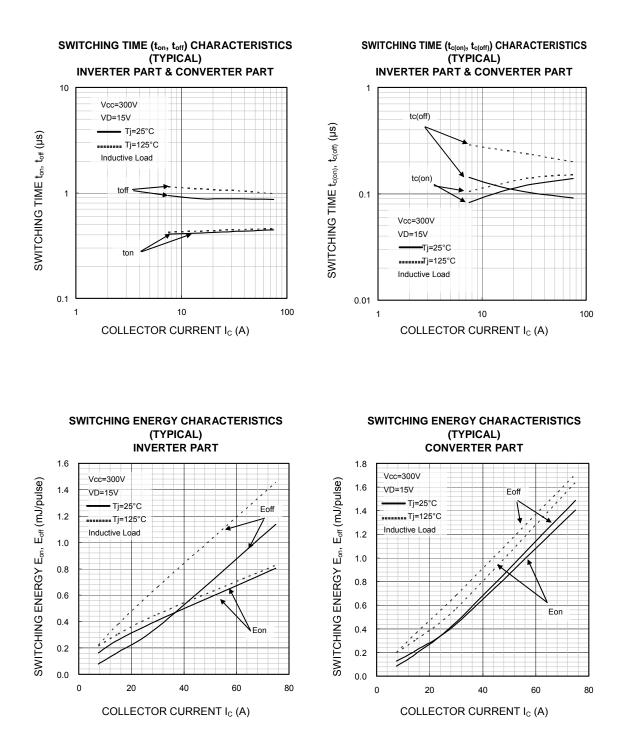
FLAT-BASE TYPE INSULATED PACKAGE

#### PERFORMANCE CURVES

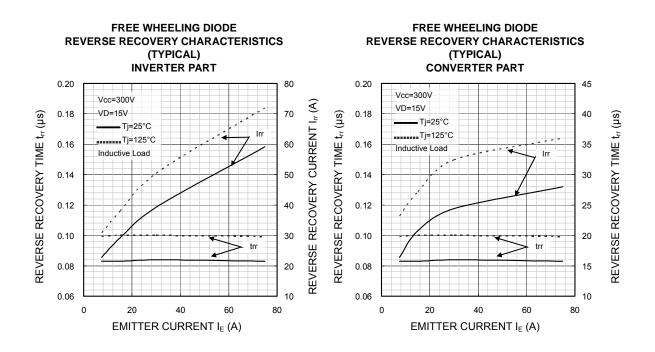


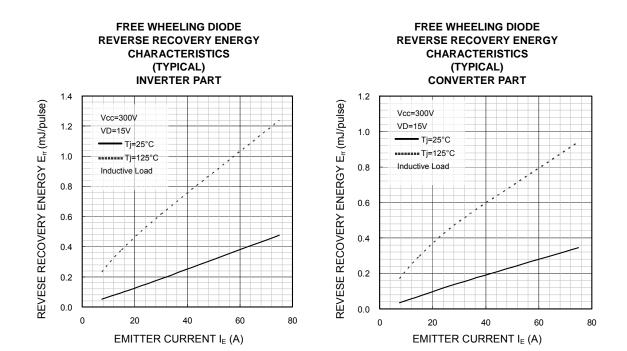


Di FORWARD VOLTAGE V<sub>FM</sub> (V)

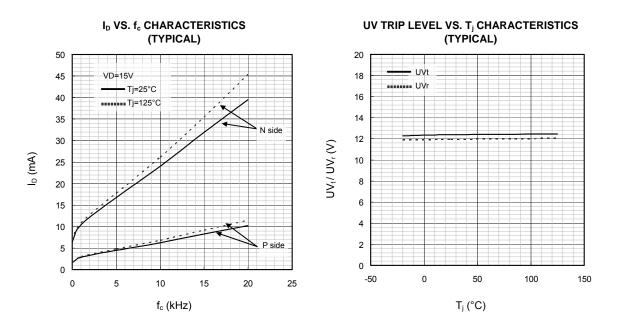


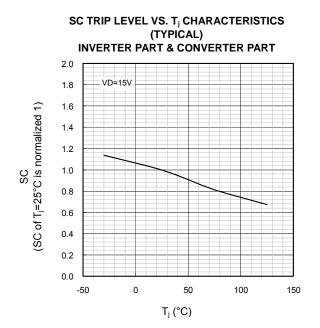




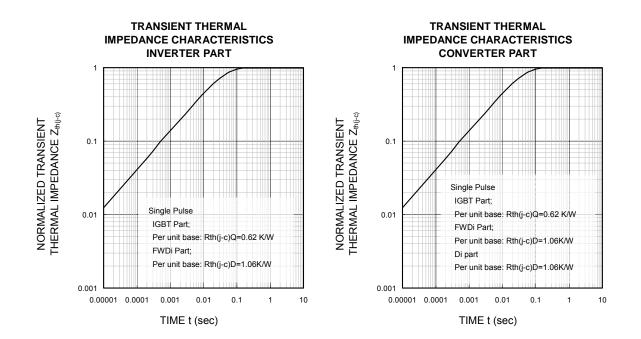














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